
The Next Generation PV Inspection System from Tordivel Solar – The Wafer Topology Measurement System

Tordivel Solar AS, an affiliate and 2008 demerger of Tordivel AS, has moved its patent pending Sawmarks Measurement System to an in-line complete Wafer Topology Measurements System.

The Wafer Topology Measurement System includes the following functions:

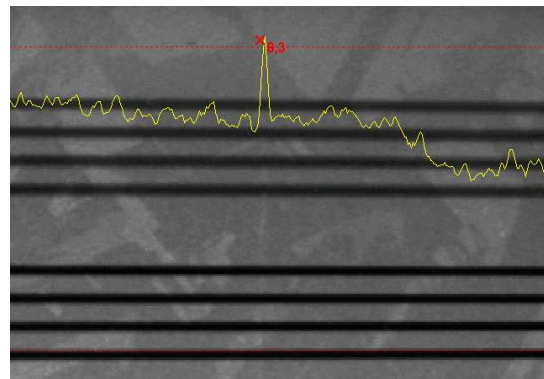
- Robust and accurate two sided **sawmarks** measurements.
- High resolution two sided wafer **surface** and **thickness** profile measurements

The wafer profile is calculated 10 mm from the edges with a resolution better than 1 μm .



Topology Measurement System

High resolution surface profiles with a lateral resolution of 0.01 mm will provide information to understand the wafer sawing process. All measurements are based on Tordivel Solar's patent pending and unique shadow measurement technique which improves accuracy and robustness by cancelling the effects of the wafer crystal patterns.



Sawmarks measurement

- Wafer **dimensions** and **corner chamfering**

The wafer dimension is performed with a resolution of 0.005 mm.

Reliable wafer measurements are secured by the **PolygonMatch™** technology, to identify the wafer position, rotation and size with state of the art sub pixel accuracy.

All Tordivel Solar's solutions are based on the Scorpion Vision Software® and include flexible interfaces such as TCP/IP, RS-232 and Profibus, OPC support, logging of the inspection results and contemporary statistical data presentation.

"Tordivel Solar's scope is to inspect wafers for defects, and provide measurement and sorting data. This with the highest reliability, most compact measurement systems and the highest precision, for low maintenance cost and the best total cost of ownership."

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